# E·XFL

# Intel - 5SGSMD6K2F40C2LN Datasheet



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Details	
Product Status	Obsolete
Number of LABs/CLBs	220000
Number of Logic Elements/Cells	583000
Total RAM Bits	46080000
Number of I/O	696
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgsmd6k2f40c2ln

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

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Transceiver Speed				Core Spe	ed Grade			
Grade	C1	C2, C2L	C3	C4	12, 12L	13, 13L	<b>I</b> 3YY	14
3		Yes	Yes	Yes		Yes	Yes (4)	Yes
GX channel—8.5 Gbps		165	165	165		165	163.7	165

#### Table 1. Stratix V GX and GS Commercial and Industrial Speed Grade Offering <sup>(1), (2), (3)</sup> (Part 2 of 2)

Notes to Table 1:

(1) C = Commercial temperature grade; I = Industrial temperature grade.

(2) Lower number refers to faster speed grade.

(3) C2L, I2L, and I3L speed grades are for low-power devices.

(4) I3YY speed grades can achieve up to 10.3125 Gbps.

Table 2 lists the industrial and commercial speed grades for the Stratix V GT devices. **Table 2. Stratix V GT Commercial and Industrial Speed Grade Offering** <sup>(1)</sup>, <sup>(2)</sup>

Transaction Oracle Oracle		Core Speed Grade						
Transceiver Speed Grade	C1	C2	12	13				
2 GX channel—12.5 Gbps GT channel—28.05 Gbps	Yes	Yes	_	_				
3 GX channel—12.5 Gbps GT channel—25.78 Gbps	Yes	Yes	Yes	Yes				

#### Notes to Table 2:

(1) C = Commercial temperature grade; I = Industrial temperature grade.

(2) Lower number refers to faster speed grade.

# **Absolute Maximum Ratings**

Absolute maximum ratings define the maximum operating conditions for Stratix V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.



Conditions other than those listed in Table 3 may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 3.	Absolute	Maximum	<b>Ratings</b>	for Stratix \	/ Devices	(Part 1 of 2)
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Symbol	Description	Minimum	Maximum	Unit
V <sub>CC</sub>	Power supply for core voltage and periphery circuitry	-0.5	1.35	V
V <sub>CCPT</sub>	Power supply for programmable power technology	-0.5	1.8	V
V <sub>CCPGM</sub>	Power supply for configuration pins	-0.5	3.9	V
V <sub>CC_AUX</sub>	Auxiliary supply for the programmable power technology	-0.5	3.4	V
V <sub>CCBAT</sub>	Battery back-up power supply for design security volatile key register	-0.5	3.9	V
V <sub>CCPD</sub>	I/O pre-driver power supply	-0.5	3.9	V
V <sub>CCIO</sub>	I/O power supply	-0.5	3.9	V

Symbol	Description	Minimum	Maximum	Unit
V <sub>CCD_FPLL</sub>	PLL digital power supply	-0.5	1.8	V
V <sub>CCA_FPLL</sub>	PLL analog power supply	-0.5	3.4	V
VI	DC input voltage	-0.5	3.8	V
TJ	Operating junction temperature	-55	125	°C
T <sub>STG</sub>	Storage temperature (No bias)	-65	150	°C
I <sub>OUT</sub>	DC output current per pin	-25	40	mA

Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 2 of 2)

Table 4 lists the absolute conditions for the transceiver power supply for Stratix V GX, GS, and GT devices.

Table 4. Transceiver Power Supply Absolute Conditions for Stratix V GX, GS, and GT Devices

Symbol	Description	Devices	Minimum	Maximum	Unit
V <sub>CCA_GXBL</sub>	Transceiver channel PLL power supply (left side)	GX, GS, GT	-0.5	3.75	V
V <sub>CCA_GXBR</sub>	Transceiver channel PLL power supply (right side)	GX, GS	-0.5	3.75	V
V <sub>CCA_GTBR</sub>	Transceiver channel PLL power supply (right side)	GT	-0.5	3.75	V
V <sub>CCHIP_L</sub>	Transceiver hard IP power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCHIP_R</sub>	Transceiver hard IP power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCHSSI_L</sub>	Transceiver PCS power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCHSSI_R</sub>	Transceiver PCS power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCR_GXBL</sub>	Receiver analog power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCR_GXBR</sub>	Receiver analog power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCR_GTBR</sub>	Receiver analog power supply for GT channels (right side)	GT	-0.5	1.35	V
V <sub>CCT_GXBL</sub>	Transmitter analog power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCT_GXBR</sub>	Transmitter analog power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCT_GTBR</sub>	Transmitter analog power supply for GT channels (right side)	GT	-0.5	1.35	V
V <sub>CCL_GTBR</sub>	Transmitter clock network power supply (right side)	GT	-0.5	1.35	V
V <sub>CCH_GXBL</sub>	Transmitter output buffer power supply (left side)	GX, GS, GT	-0.5	1.8	V
V <sub>CCH_GXBR</sub>	Transmitter output buffer power supply (right side)	GX, GS, GT	-0.5	1.8	V

## **Maximum Allowed Overshoot and Undershoot Voltage**

During transitions, input signals may overshoot to the voltage shown in Table 5 and undershoot to -2.0 V for input currents less than 100 mA and periods shorter than 20 ns.

## I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

Table 9. I/	0 Pin Leakage	<b>Current for Stratix </b>	/ Devices <sup>(1)</sup>
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Symbol	Description	Conditions	Min	Тур	Max	Unit
I <sub>I</sub>	Input pin	$V_I = 0 V \text{ to } V_{CCIOMAX}$	-30	—	30	μA
I <sub>0Z</sub>	Tri-stated I/O pin	$V_0 = 0 V$ to $V_{CCIOMAX}$	-30		30	μA

## Note to Table 9:

(1) If  $V_0 = V_{CCIO}$  to  $V_{CCIOMax}$ , 100  $\mu$ A of leakage current per I/O is expected.

## **Bus Hold Specifications**

Table 10 lists the Stratix V device family bus hold specifications.

Table 10. Bus Hold Parameters for Stratix V Devices

							Va	CI0	-		-		
Parameter	Symbol	Conditions	1.2 V		1.	1.5 V 1.8		.8 V 2.		5 V	3.0 V		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I <sub>SUSL</sub>	V <sub>IN</sub> > V <sub>IL</sub> (maximum)	22.5	_	25.0	_	30.0	_	50.0	_	70.0	_	μA
High sustaining current	I <sub>SUSH</sub>	V <sub>IN</sub> < V <sub>IH</sub> (minimum)	-22.5	_	-25.0	_	-30.0	_	-50.0	_	-70.0	_	μA
Low overdrive current	I <sub>odl</sub>	$0V < V_{IN} < V_{CCIO}$	_	120	_	160	_	200	_	300	_	500	μA
High overdrive current	I <sub>odh</sub>	$0V < V_{IN} < V_{CCIO}$		-120		-160	_	-200		-300	_	-500	μA
Bus-hold trip point	V <sub>trip</sub>	_	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

## **On-Chip Termination (OCT) Specifications**

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices <sup>(1)</sup> (Part 1 of 2)

Symbol			Calibration Accuracy				
	Description	Conditions	C1	C2,12	C3,I3, I3YY	C4,14	Unit
25-Ω R <sub>S</sub>	Internal series termination with calibration (25- $\Omega$ setting)	V <sub>CCI0</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%

			Calibration Accuracy				
Symbol	Description	Conditions	C1	C2,12	C3,I3, I3YY	C4,14	Unit
50-Ω R <sub>S</sub>	Internal series termination with calibration (50- $\Omega$ setting)	V <sub>CCI0</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%
34-Ω and 40-Ω R <sub>S</sub>	Internal series termination with calibration (34- $\Omega$ and 40- $\Omega$ setting)	V <sub>CCI0</sub> = 1.5, 1.35, 1.25, 1.2 V	±15	±15	±15	±15	%
48-Ω, 60-Ω, 80-Ω, and 240-Ω R <sub>S</sub>	Internal series termination with calibration (48- $\Omega$ , 60- $\Omega$ , 80- $\Omega$ , and 240- $\Omega$ setting)	V <sub>CCI0</sub> = 1.2 V	±15	±15	±15	±15	%
50-Ω R <sub>T</sub>	Internal parallel termination with calibration (50-Ω setting)	V <sub>CCIO</sub> = 2.5, 1.8, 1.5, 1.2 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
20- $Ω$ , 30- $Ω$ , 40- $Ω$ ,60- $Ω$ , and 120- $Ω$ R <sub>T</sub>	Internal parallel termination with calibration ( $20 \cdot \Omega$ , $30 \cdot \Omega$ , $40 \cdot \Omega$ , $60 \cdot \Omega$ , and $120 \cdot \Omega$ setting)	V <sub>CCI0</sub> = 1.5, 1.35, 1.25 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
60-Ω and 120-Ω $R_T$	Internal parallel termination with calibration (60- $\Omega$ and 120- $\Omega$ setting)	V <sub>CCI0</sub> = 1.2	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
$\begin{array}{l} \textbf{25-}\Omega\\ \textbf{R}_{S\_left\_shift} \end{array}$	Internal left shift series termination with calibration (25- $\Omega$ R <sub>S_left_shift</sub> setting)	V <sub>CCI0</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%

Table 11. OCT Calibration Accurat	y Specifications for Stratix V Devices <sup>(1)</sup> (	(Part 2 of 2)
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## Note to Table 11:

(1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance to PVT changes.

			<b>Resistance Tolerance</b>						
Symbol	Symbol Description		C1	C2,I2	C3, I3, I3YY	C4, I4	Unit		
25-Ω R, 50-Ω R <sub>S</sub>	Internal series termination without calibration (25- $\Omega$ setting)	$V_{CCIO} = 3.0$ and 2.5 V	±30	±30	±40	±40	%		
25-Ω R <sub>S</sub>	Internal series termination without calibration (25-Ω setting)	$V_{CCI0} = 1.8$ and 1.5 V	±30	±30	±40	±40	%		
25-Ω R <sub>S</sub>	Internal series termination without calibration (25-Ω setting)	V <sub>CCI0</sub> = 1.2 V	±35	±35	±50	±50	%		

I/O		V <sub>ccio</sub> (V)		V <sub>DIF(</sub>	<sub>DC)</sub> (V)	/) V <sub>X(AC)</sub>		V <sub>X(AC)</sub> (V)		V <sub>CM(DC)</sub> (V	V <sub>DIF(AC)</sub> (V)		
Standard	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Тур	Max	Min	Max
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V <sub>CCI0</sub> + 0.3	_	0.5* V <sub>CCI0</sub>	_	0.4* V <sub>CCI0</sub>	0.5* V <sub>CCIO</sub>	0.6* V <sub>CCIO</sub>	0.3	V <sub>CCI0</sub> + 0.48
HSUL-12	1.14	1.2	1.3	0.26	0.26	0.5*V <sub>CCI0</sub> - 0.12	0.5* V <sub>CCIO</sub>	0.5*V <sub>CCI0</sub> + 0.12	0.4* V <sub>CCIO</sub>	0.5* V <sub>CCIO</sub>	0.6* V <sub>CCIO</sub>	0.44	0.44

#### Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 2 of 2)

## Table 22. Differential I/O Standard Specifications for Stratix V Devices (7)

I/O	Vc	<sub>cio</sub> (V)	(10)	V <sub>ID</sub> (mV) <sup>(8)</sup>				V <sub>ICM(DC)</sub> (V)		Vo	<sub>D</sub> (V) (	5)	V <sub>осм</sub> (V) <i>(6)</i>		
Standard	Min	Тур	Max	Min	Condition	Max	Min	Condition	Max	Min	Тур	Max	Min	Тур	Max
PCML	Tran	ismitte			•		•	of the high-s I/O pin speci	•						For
2.5 V	2.375	2.5	2.625	100	V <sub>CM</sub> =	_	0.05	D <sub>MAX</sub> ≤ 700 Mbps	1.8	0.247	_	0.6	1.125	1.25	1.375
LVDS <sup>(1)</sup>	2.375	2.0	2.025	100	1.25 V	_	1.05	D <sub>MAX</sub> > 700 Mbps	1.55	0.247	_	0.6	1.125	1.25	1.375
BLVDS (5)	2.375	2.5	2.625	100	_	_		—	_	_	_		_		
RSDS (HIO) <sup>(2)</sup>	2.375	2.5	2.625	100	V <sub>CM</sub> = 1.25 V	_	0.3	—	1.4	0.1	0.2	0.6	0.5	1.2	1.4
Mini- LVDS (HIO) <sup>(3)</sup>	2.375	2.5	2.625	200		600	0.4	_	1.325	0.25	_	0.6	1	1.2	1.4
LVPECL (4			_	300		_	0.6	D <sub>MAX</sub> ≤ 700 Mbps	1.8		_	_			
), (9)		_		300	_	_	1	D <sub>MAX</sub> > 700 Mbps	1.6		_	_			—

Notes to Table 22:

(1) For optimized LVDS receiver performance, the receiver voltage input range must be between 1.0 V to 1.6 V for data rates above 700 Mbps, and 0 V to 1.85 V for data rates below 700 Mbps.

(2) For optimized RSDS receiver performance, the receiver voltage input range must be between 0.25 V to 1.45 V.

(3) For optimized Mini-LVDS receiver performance, the receiver voltage input range must be between 0.3 V to 1.425 V.

- (4) For optimized LVPECL receiver performance, the receiver voltage input range must be between 0.85 V to 1.75 V for data rate above 700 Mbps and 0.45 V to 1.95 V for data rate below 700 Mbps.
- (5) There are no fixed  $V_{ICM}$ ,  $V_{OD}$ , and  $V_{OCM}$  specifications for BLVDS. They depend on the system topology.
- (6) RL range:  $90 \le RL \le 110 \Omega$ .
- (7) The 1.4-V and 1.5-V PCML transceiver I/O standard specifications are described in "Transceiver Performance Specifications" on page 18.
- (8) The minimum VID value is applicable over the entire common mode range, VCM.
- (9) LVPECL is only supported on dedicated clock input pins.
- (10) Differential inputs are powered by VCCPD which requires 2.5 V.

# **Power Consumption**

Altera offers two ways to estimate power consumption for a design—the Excel-based Early Power Estimator and the Quartus<sup>®</sup> II PowerPlay Power Analyzer feature.

- You typically use the interactive Excel-based Early Power Estimator before designing the FPGA to get a magnitude estimate of the device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The PowerPlay Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yields very accurate power estimates.
- **\*** For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

Symbol/	Conditions	Trai	nsceive Grade	r Speed 1	Trai	nsceive Grade	r Speed 2	Trai	nsceive Grade	r Speed 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Spread-spectrum downspread	PCle	_	0 to 0.5	_	_	0 to 0.5		_	0 to 0.5	_	%
On-chip termination resistors <sup>(21)</sup>	_	_	100		_	100		_	100		Ω
Absolute V <sub>MAX</sub> <sup>(5)</sup>	Dedicated reference clock pin	_	_	1.6	_	_	1.6	_	_	1.6	V
	RX reference clock pin	_	_	1.2	_		1.2		_	1.2	
Absolute $V_{\text{MIN}}$	—	-0.4	—		-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	_	200	_	1600	200	_	1600	200	_	1600	mV
V <sub>ICM</sub> (AC	Dedicated reference clock pin	1050/	1000/90	00/850 <sup>(2)</sup>	1050/	1000/90	00/850 <sup>(2)</sup>	1050/1000/900/850 (2)			mV
coupled) <sup>(3)</sup>	RX reference clock pin	1.	.0/0.9/0	.85 <sup>(4)</sup>	1.	0/0.9/0	.85 <sup>(4)</sup>	1.	0/0.9/0	.85 <sup>(4)</sup>	V
V <sub>ICM</sub> (DC coupled)	HCSL I/O standard for PCIe reference clock	250		550	250		550	250		550	mV
	100 Hz	—	—	-70	—	—	-70	—	—	-70	dBc/Hz
Transmitter	1 kHz			-90			-90		—	-90	dBc/Hz
REFCLK Phase Noise	10 kHz	—	—	-100	—	—	-100	—	—	-100	dBc/Hz
(622 MHz) <sup>(20)</sup>	100 kHz			-110		—	-110	—	—	-110	dBc/Hz
	≥1 MHz	—	—	-120	—	—	-120	—	—	-120	dBc/Hz
Transmitter REFCLK Phase Jitter (100 MHz) <sup>(17)</sup>	10 kHz to 1.5 MHz (PCle)	_	_	3	_	_	3	_	_	3	ps (rms)
R <sub>REF</sub> (19)	_		1800 ±1%		_	1800 ±1%			180 0 ±1%		Ω
Transceiver Clocks	S										
fixedclk clock frequency	PCIe Receiver Detect		100 or 125	_	_	100 or 125	_	_	100 or 125	_	MHz

# Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 2 of 7)

Symbol/ Description	Conditions	Tra	nsceive Grade	r Speed 1	Tra	nsceive Grade	r Speed 2	Trai	nsceive Grade	r Speed 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
	85– $\Omega$ setting		85 ± 30%		—	85 ± 30%			85 ± 30%		Ω
Differential on-	100–Ω setting	_	100 ± 30%		_	100 ± 30%		_	100 ± 30%		Ω
chip termination resistors <sup>(21)</sup>	120–Ω setting	_	120 ± 30%		_	120 ± 30%		_	120 ± 30%		Ω
	150-Ω setting	_	150 ± 30%	_	_	150 ± 30%		_	150 ± 30%		Ω
	V <sub>CCR_GXB</sub> = 0.85 V or 0.9 V full bandwidth		600		_	600	_		600		mV
V <sub>ICM</sub> (AC and DC coupled)	V <sub>CCR_GXB</sub> = 0.85 V or 0.9 V half bandwidth	_	600	_	_	600	_	_	600	_	mV
coupleu)	V <sub>CCR_GXB</sub> = 1.0 V/1.05 V full bandwidth	_	700		_	700			700		mV
	V <sub>CCR_GXB</sub> = 1.0 V half bandwidth		750	_	_	750	_	_	750	_	mV
t <sub>LTR</sub> <sup>(11)</sup>	_	_	—	10	—	—	10	—	—	10	μs
t <sub>LTD</sub> (12)	_	4			4			4			μs
t <sub>LTD_manual</sub> <sup>(13)</sup>		4			4			4	_		μs
t <sub>LTR_LTD_manual</sub> <sup>(14)</sup>		15			15	—		15	—		μs
Run Length	_	_		200		—	200		—	200	UI
Programmable equalization (AC Gain) <sup>(10)</sup>	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)			16	_		16	_		16	dB

 Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 4 of 7)

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
t <sub>pll_lock</sub> (16)	_			10		—	10	—		10	μs

#### Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 7 of 7)

#### Notes to Table 23:

(2) The reference clock common mode voltage is equal to the V<sub>CCR\_GXB</sub> power supply level.

(3) This supply must be connected to 1.0 V if the transceiver is configured at a data rate > 6.5 Gbps, and to 1.05 V if configured at a data rate > 10.3 Gbps when DFE is used. For data rates up to 6.5 Gbps, you can connect this supply to 0.85 V.

- (4) This supply follows VCCR\_GXB.
- (5) The device cannot tolerate prolonged operation at this absolute maximum.
- (6) The differential eye opening specification at the receiver input pins assumes that **Receiver Equalization** is disabled. If you enable **Receiver Equalization**, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.
- (7) The Quartus II software automatically selects the appropriate slew rate depending on the configured data rate or functional mode.
- (8) The input reference clock frequency options depend on the data rate and the device speed grade.
- (9) The line data rate may be limited by PCS-FPGA interface speed grade.
- (10) Refer to Figure 1 for the GX channel AC gain curves. The total effective AC gain is the AC gain minus the DC gain.
- (11) t<sub>LTR</sub> is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.
- (12) t<sub>LTD</sub> is time required for the receiver CDR to start recovering valid data after the rx\_is\_lockedtodata signal goes high.
- (13) t<sub>LTD\_manual</sub> is the time required for the receiver CDR to start recovering valid data after the rx\_is\_lockedtodata signal goes high when the CDR is functioning in the manual mode.
- (14)  $t_{LTR\_LTD\_manual}$  is the time the receiver CDR must be kept in lock to reference (LTR) mode after the rx\_is\_lockedtoref signal goes high when the CDR is functioning in the manual mode.
- (15)  $t_{pll_powerdown}$  is the PLL powerdown minimum pulse width.
- (16) t<sub>pll lock</sub> is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.
- (17) To calculate the REFCLK rms phase jitter requirement for PCIe at reference clock frequencies other than 100 MHz, use the following formula: REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.
- (18) The maximum peak to peak differential input voltage  $V_{ID}$  after device configuration is equal to 4 × (absolute  $V_{MAX}$  for receiver pin  $V_{ICM}$ ).
- (19) For ES devices,  $R_{BEF}$  is 2000  $\Omega \pm 1\%$ .
- (20) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20\*log(f/622).
- (21) SFP/+ optical modules require the host interface to have RD+/- differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (22) Refer to Figure 2.
- (23) For oversampling designs to support data rates less than the minimum specification, the CDR needs to be in LTR mode only.
- (24) I3YY devices can achieve data rates up to 10.3125 Gbps.
- (25) When you use fPLL as a TXPLL of the transceiver.
- (26) REFCLK performance requires to meet transmitter REFCLK phase noise specification.
- (27) Minimum eye opening of 85 mV is only for the unstressed input eye condition.

<sup>(1)</sup> Speed grades shown in Table 23 refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the Stratix V Device Overview.

Table 26 shows the approximate maximum data rate using the 10G PCS.

Table 26. Stratix V 10G PCS Approximate Maximum Data Rate (1)
---------------------------------------------------------------

Mada (2)	Transceiver	PMA Width	64	40	40	40	32	32
Mode <sup>(2)</sup>	Speed Grade	PCS Width	64	66/67	50	40	64/66/67	32
	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6
	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5
	2	C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
FIFO or Register		C1, C2, C2L, I2, I2L core speed grade						
	2	C3, I3, I3L core speed grade			8.5	Gbps		
	3	C4, I4 core speed grade						
		I3YY core speed grade			10.31	25 Gbps		

Notes to Table 26:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 5 of 5) (	Fransceiver Specifications for Stratix V GT Devices (Part 5 of 5) <sup>(1)</sup>
-------------------------------------------------------------------------------	----------------------------------------------------------------------------------

Symbol/ Description	Conditions		Transceivei peed Grade		S	Unit		
Description		Min	Тур	Max	Min	Тур	Max	
t <sub>pll_lock</sub> <sup>(14)</sup>	—	—	_	10	—	—	10	μs

#### Notes to Table 28:

- (1) Speed grades shown refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the Stratix V Device Overview.
- (2) The reference clock common mode voltage is equal to the VCCR\_GXB power supply level.
- (3) The device cannot tolerate prolonged operation at this absolute maximum.
- (4) The differential eye opening specification at the receiver input pins assumes that receiver equalization is disabled. If you enable receiver equalization, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.
- (5) Refer to Figure 5 for the GT channel AC gain curves. The total effective AC gain is the AC gain minus the DC gain.
- (6) Refer to Figure 6 for the GT channel DC gain curves.
- (7) CFP2 optical modules require the host interface to have the receiver data pins differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (8) Specifications for this parameter are the same as for Stratix V GX and GS devices. See Table 23 for specifications.
- (9) t<sub>1 TR</sub> is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.
- (10) t<sub>LTD</sub> is time required for the receiver CDR to start recovering valid data after the rx is lockedtodata signal goes high.
- (11)  $t_{LTD\_manual}$  is the time required for the receiver CDR to start recovering valid data after the rx\_is\_lockedtodata signal goes high when the CDR is functioning in the manual mode.
- (12) t<sub>LTR\_LTD\_manual</sub> is the time the receiver CDR must be kept in lock to reference (LTR) mode after the rx\_is\_lockedtoref signal goes high when the CDR is functioning in the manual mode.
- (13) tpll\_powerdown is the PLL powerdown minimum pulse width.
- (14) tpll lock is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.
- (15) To calculate the REFCLK rms phase jitter requirement for PCle at reference clock frequencies other than 100 MHz, use the following formula: REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.
- (16) The maximum peak to peak differential input voltage  $V_{ID}$  after device configuration is equal to 4 × (absolute  $V_{MAX}$  for receiver pin  $V_{ICM}$ ).
- (17) For ES devices, RREF is 2000  $\Omega \pm 1\%$ .
- (18) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20\*log(f/622).
- (19) SFP/+ optical modules require the host interface to have RD+/- differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (20) Refer to Figure 4.
- (21) For oversampling design to support data rates less than the minimum specification, the CDR needs to be in LTR mode only.
- (22) This supply follows VCCR\_GXB for both GX and GT channels.
- (23) When you use fPLL as a TXPLL of the transceiver.

Figure 4 shows the differential transmitter output waveform.



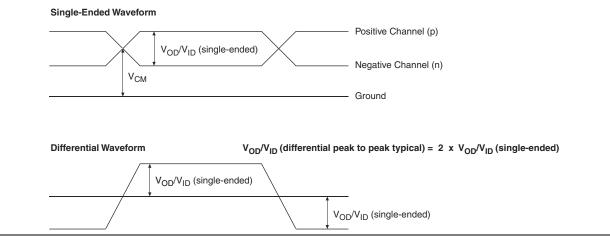


Figure 5 shows the Stratix V AC gain curves for GT channels.

Figure 5. AC Gain Curves for GT Channels

Figure 6 shows the Stratix V DC gain curves for GT channels.

Figure 6. DC Gain Curves for GT Channels

# **Transceiver Characterization**

This section summarizes the Stratix V transceiver characterization results for compliance with the following protocols:

- Interlaken
- 40G (XLAUI)/100G (CAUI)
- 10GBase-KR
- QSGMII
- XAUI
- SFI
- Gigabit Ethernet (Gbe / GIGE)
- SPAUI
- Serial Rapid IO (SRIO)
- CPRI
- OBSAI
- Hyper Transport (HT)
- SATA
- SAS
- CEI

# **PLL Specifications**

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to  $85^{\circ}$ C) and the industrial junction temperature range (-40° to  $100^{\circ}$ C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Тур	Max	Unit
	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	_	800 (1)	MHz
f <sub>IN</sub>	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	_	800 (1)	MHz
	Input clock frequency (C4, I4 speed grades)	5	—	650 <sup>(1)</sup>	MHz
f <sub>INPFD</sub>	Input frequency to the PFD	5	—	325	MHz
f <sub>finpfd</sub>	Fractional Input clock frequency to the PFD	50	—	160	MHz
	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	_	1600	MHz
f <sub>VCO</sub>	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	_	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	_	1300	MHz
t <sub>einduty</sub>	Input clock or external feedback clock input duty cycle	40	—	60	%
	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)		_	717 <sup>(2)</sup>	MHz
f <sub>out</sub>	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	_	_	650 <sup>(2)</sup>	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)		_	580 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)		_	800 (2)	MHz
f <sub>out_ext</sub>	Output frequency for an external clock output (C3, I3, I3L speed grades)		_	667 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C4, I4 speed grades)		_	553 <sup>(2)</sup>	MHz
t <sub>outduty</sub>	Duty cycle for a dedicated external clock output (when set to <b>50%</b> )	45	50	55	%
t <sub>FCOMP</sub>	External feedback clock compensation time	_	—	10	ns
f <sub>dyconfigclk</sub>	Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code>	_	_	100	MHz
t <sub>LOCK</sub>	Time required to lock from the end-of-device configuration or deassertion of areset		_	1	ms
t <sub>olock</sub>	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)		_	1	ms
	PLL closed-loop low bandwidth		0.3	_	MHz
f <sub>CLBW</sub>	PLL closed-loop medium bandwidth		1.5	_	MHz
	PLL closed-loop high bandwidth (7)		4	_	MHz
t <sub>PLL_PSERR</sub>	Accuracy of PLL phase shift			±50	ps
t <sub>ARESET</sub>	Minimum pulse width on the areset signal	10		_	ns

Symbol	Parameter	Min	Тур	Max	Unit
+ (3) (4)	Input clock cycle-to-cycle jitter ( $f_{REF} \ge 100 \text{ MHz}$ )	_	—	0.15	UI (p-p)
t <sub>INCCJ</sub> <sup>(3),</sup> <sup>(4)</sup>	Input clock cycle-to-cycle jitter (f <sub>REF</sub> < 100 MHz)	-750	_	+750	ps (p-p)
t	Period Jitter for dedicated clock output (f_{OUT} $\geq$ 100 MHz)	_	_	175 <sup>(1)</sup>	ps (p-p)
t <sub>outpj_dc</sub> <sup>(5)</sup>	Period Jitter for dedicated clock output (f <sub>OUT</sub> < 100 MHz)	_		17.5 <sup>(1)</sup>	mUI (p-p)
+ (5)	Period Jitter for dedicated clock output in fractional PLL ( $f_{0UT} \geq 100 \mbox{ MHz})$	_	_	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
t <sub>foutpj_dc</sub> <sup>(5)</sup>	Period Jitter for dedicated clock output in fractional PLL (f <sub>OUT</sub> < 100 MHz)	_	_	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
+	Cycle-to-Cycle Jitter for a dedicated clock output ( $f_{OUT} \ge 100 \text{ MHz}$ )	_	_	175	ps (p-p)
t <sub>outccj_dc</sub> <sup>(5)</sup>	Cycle-to-Cycle Jitter for a dedicated clock output ( $f_{OUT} < 100 \text{ MHz}$ )	_	_	17.5	mUI (p-p)
t <sub>foutccj_dc</sub> (5)	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ( $f_{OUT} \geq 100 \mbox{ MHz})$	_	_	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
4OUTCCJ_DC	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ( $f_{OUT} < 100 \text{ MHz}$ )+		_	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
t <sub>outpj_10</sub> (5),	Period Jitter for a clock output on a regular I/O in integer PLL (f_{0UT} $\geq$ 100 MHz)		_	600	ps (p-p)
(8)	Period Jitter for a clock output on a regular I/O (f <sub>OUT</sub> < 100 MHz)	_	_	60	mUI (p-p)
t <sub>FOUTPJ_IO</sub> (5),	Period Jitter for a clock output on a regular I/O in fractional PLL ( $f_{OUT} \geq 100~\text{MHz})$	_	_	600 (10)	ps (p-p)
(8), (11)	Period Jitter for a clock output on a regular I/O in fractional PLL (f <sub>OUT</sub> < 100 MHz)	_	_	60 <sup>(10)</sup>	mUI (p-p)
t <sub>outccj_10</sub> <sup>(5),</sup>	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL (f_{OUT} $\geq$ 100 MHz)	—	_	600	ps (p-p)
(8)	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ( $f_{OUT}$ < 100 MHz)		_	60 <sup>(10)</sup>	mUI (p-p)
t <sub>foutccj_10</sub> <sup>(5),</sup>	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL (f_{OUT} $\geq$ 100 MHz)	_	_	600 <sup>(10)</sup>	ps (p-p)
(8), (11)	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ( $f_{OUT} < 100 \text{ MHz}$ )	—	_	60	mUI (p-p)
t <sub>casc_outpj_dc</sub>	Period Jitter for a dedicated clock output in cascaded PLLs (f_{0UT} $\geq$ 100 MHz)		_	175	ps (p-p)
(5), (6)	Period Jitter for a dedicated clock output in cascaded PLLs (f <sub>OUT</sub> < 100 MHz)			17.5	mUI (p-p)
f <sub>drift</sub>	Frequency drift after PFDENA is disabled for a duration of 100 $\mu\text{s}$		_	±10	%
dK <sub>BIT</sub>	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
k <sub>value</sub>	Numerator of Fraction	128	8388608	2147483648	

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

		Resour	ces Used			Pe	erforman	ce			
Memory	Mode	ALUTS	Memory	C1	C2, C2L	C3	C4	12, 12L	13, 13L, 13YY	14	Unit
	Single-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port with the read-during-write option set to <b>Old Data</b> , all supported widths	0	1	525	525	455	400	525	455	400	MHz
M20K Block	Simple dual-port with ECC enabled, 512 × 32	0	1	450	450	400	350	450	400	350	MHz
	Simple dual-port with ECC and optional pipeline registers enabled, 512 × 32	0	1	600	600	500	450	600	500	450	MHz
	True dual port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	ROM, all supported widths	0	1	700	700	650	550	700	500	450	MHz

## Table 33. Memory Block Performance Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

## Notes to Table 33:

(1) To achieve the maximum memory block performance, use a memory block clock that comes through global clock routing from an on-chip PLL set to **50**% output duty cycle. Use the Quartus II software to report timing for this and other memory block clocking schemes.

(2) When you use the error detection cyclical redundancy check (CRC) feature, there is no degradation in F<sub>MAX</sub>.

(3) The F<sub>MAX</sub> specification is only achievable with Fitter options, MLAB Implementation In 16-Bit Deep Mode enabled.

# **Temperature Sensing Diode Specifications**

Table 34 lists the internal TSD specification.

#### **Table 34. Internal Temperature Sensing Diode Specification**

Temperature Range	Accuracy	Offset Calibrated Option	Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
–40°C to 100°C	±8°C	No	1 MHz, 500 KHz	< 100 ms	8 bits	8 bits

Table 35 lists the specifications for the Stratix V external temperature sensing diode.

Description	Min	Тур	Max	Unit
I <sub>bias</sub> , diode source current	8	—	200	μA
V <sub>bias,</sub> voltage across diode	0.3	—	0.9	V
Series resistance		—	< 1	Ω
Diode ideality factor	1.006	1.008	1.010	

# **Periphery Performance**

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface. General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.

The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

# **High-Speed I/O Specification**

Table 36 lists high-speed I/O timing for Stratix V devices.

Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 1 of 4)

Sumbol	Conditiono		C1			C2L, I	2, I2L	C3,	13, 13L	., <b>I</b> 3YY		C4,I	4	Ilmit
Symbol	Symbol Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
f <sub>HSCLK_in</sub> (input clock frequency) True Differential I/O Standards	Clock boost factor W = 1 to 40 $^{(4)}$	5		800	5	_	800	5		625	5		525	MHz
f <sub>HSCLK_in</sub> (input clock frequency) Single Ended I/O Standards <sup>(3)</sup>	Clock boost factor W = 1 to 40 $^{(4)}$	5		800	5		800	5		625	5		525	MHz
f <sub>HSCLK_in</sub> (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 $^{(4)}$	5		520	5	_	520	5		420	5		420	MHz
f <sub>HSCLK_OUT</sub> (output clock frequency)	_	5	_	800	5	_	800	5	_	625 (5)	5	_	525 (5)	MHz

Figure 7 shows the dynamic phase alignment (DPA) lock time specifications with the DPA PLL calibration option enabled.

Figure 7. DPA Lock Time Specification with DPA PLL Calibration Enabled

rx_reset	i		
rx_dpa_locked			

Table 37 lists the DPA lock time specifications for Stratix V devices.

Table 37. DPA Lock Time Specifications for Stratix V GX Devices Only (1), (2), (3)

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions <sup>(4)</sup>	Maximum
SPI-4	0000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
Wiscenardous	01010101	8	32	640 data transitions

#### Notes to Table 37:

(1) The DPA lock time is for one channel.

(2) One data transition is defined as a 0-to-1 or 1-to-0 transition.

(3) The DPA lock time stated in this table applies to both commercial and industrial grade.

(4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 8 shows the **LVDS** soft-clock data recovery (CDR)/DPA sinusoidal jitter tolerance specification for a data rate  $\geq$  1.25 Gbps. Table 38 lists the **LVDS** soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate  $\geq$  1.25 Gbps.





	Member		Active Serial (1)	)	Fast Passive Parallel <sup>(2)</sup>			
Variant	Code	Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)	
	D3	4	100	0.344	32	100	0.043	
	D4	4	100	0.534	32	100	0.067	
GS	D4	4	100	0.344	32	100	0.043	
65	D5	4	100	0.534	32	100	0.067	
	D6	4	100	0.741	32	100	0.093	
	D8	4	100	0.741	32	100	0.093	
Е	E9	4	100	0.857	32	100	0.107	
	EB	4	100	0.857	32	100	0.107	

Table 48. Minimum Configuration Time Estimation for Stratix V Devices

#### Notes to Table 48:

(1) DCLK frequency of 100 MHz using external CLKUSR.

(2) Max FPGA FPP bandwidth may exceed bandwidth available from some external storage or control logic.

# **Fast Passive Parallel Configuration Timing**

This section describes the fast passive parallel (FPP) configuration timing parameters for Stratix V devices.

# DCLK-to-DATA[] Ratio for FPP Configuration

FPP configuration requires a different DCLK-to-DATA[]ratio when you enable the design security, decompression, or both features. Table 49 lists the DCLK-to-DATA[]ratio for each combination.

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
	Disabled	Disabled	1
FPP ×8	Disabled	Enabled	1
FFF X0	Enabled	Disabled	2
	Enabled	Enabled	2
	Disabled	Disabled	1
FPP ×16	Disabled	Enabled	2
	Enabled	Disabled	4
	Enabled	Enabled	4

 Table 49. DCLK-to-DATA[] Ratio <sup>(1)</sup> (Part 1 of 2)